Notice of References Cited	Application/Control No. 10/500,511	Applicant(s)/Patent Under Reexamination BADYLAK ET AL.		
	Examiner	Art Unit	Page 1 of 1	
	Shin-Lin Chen	1632		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,734,018	05-2004	Wolfinbarger et al.	435/378
*	В	US-6,866,686	03-2005	Ollerenshaw et al.	623/23.72
	U	US-			
	ם	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	7	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	C			
	>			
	w			
	х			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.